

Notice of References Cited	Application/Control No. 09/862,814	Applicant(s)/Patent Under Reexamination SEIBEL ET AL.	
	Examiner Kuen S Lu	Art Unit 2177	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,401,118	06-2002	Thomas, Jason B.	709/224
	B	US-6,105,055	08-2000	Pizano et al.	709/204
	C	US-2002/0072982 A1	06-2002	Barton et al.	705/26
	D	US-6,510,432	01-2003	Doyle, Ronald Patrick	707/10
	E	US-6,282,548	08-2001	Burner et al.	707/104.1
	F	US-6,480,885	11-2002	Olivier, Michael	709/207
	G	US-2002/0032725 A1	03-2002	Araujo et al.	709/203
	H	US-2002/0107701 A1	08-2002	Batty et al.	705/1
	I	US-2002/0032603 A1	03-2002	Yeiser, John O.	705/14
	J	US-2002/0143870 A1	10-2002	Rau, Franz G.	709/204
	K	US-2001/0052003 A1	12-2001	Seki et al.	709/219
	L	US-2002/0073058 A1	06-2002	Kremer et al.	707/1
	M	US-2002/0161685 A1	10-2002	Dwinnell, Michael	705/36

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

